

650V Super-junction Power MOSFET

Description

650V Super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The Multi-EPI SJ MOSFET provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler, designed by Wuxi Unigroup Microelectronics Company.

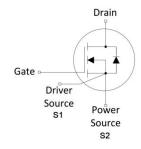
Features

- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- Easy to use/drive
- RoHS compliant

Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- Charger







Device Marking and Package Information

Device	Package	Marking	
TPG65R175MH	DFN 8*8	65R175M	

Key Performance Parameters

Parameter	Value	Unit
V _{DS} @ T _{j,max}	700	V
R _{DS(on),max}	0.175	Ω
$Q_{g,typ}$	38.8	nC
I _D	20	A
I _{D,pulse}	60	A
E _{OSS} @ 400V	4.66	μЈ
Body Diode di _F /dt	500	A/µs



Absolute Maximum Ratings T _C = 25°C, unless otherwise noted					
Parameter			Symbol	Value	Unit
Continuous Drain Current	T _C = 25°C		I _D	20	Α
Continuodo Brain Carrent	T _C = 100°C			12	^
Pulsed Drain Current		(note1)	I _{D,pulse}	60	Α
Gate-Source Voltage			V_{GSS}	±30	V
Single Pulse Avalanche Energ	у	(note2)	E _{AS}	484	mJ
Repetitive Avalanche Energy (note2)			E _{AR}	0.7	mJ
Avalanche Current			I _{AR}	3.5	Α
MOSFET dv/dt Ruggedness, V _{DS} = 0480V			dv/dt	50	V/ns
Power Dissipation For DFN 8*8			P_D	151	W
Continuous Diode Forward Current			Is	17	Α
Diode Pulsed Current (note1)		(note1)	I _{S,pulse}	60] ^
Reverse Diode dv/dt (note3)		(note3)	dv/dt	15	V/ns
Maximum Diode Commutation Speed (note3)		di _f /dt	500	A/μs	
Operating Junction and Storage Temperature Range		T_J,T_stg	-55~+150	°C	

Thermal Resistance For DFN 8*8				
Parameter	Symbol Value		Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	0.83	°C/W	
Thermal Resistance, Junction-to-Ambient	R_{thJA}	62	C/VV	



			Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static Characteristics							
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_D = 250\mu A$	650			V	
Zero Gate Voltage Drain Current		$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	μA	
Zelo Gale Vollage Dialii Guilelli	I _{DSS}	V _{DS} = 650V, V _{GS} = 0V, T _J = 150°C			100		
Gate-Source Leakage Current	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.5	V	
Drain-Source On-State-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D = 10A		0.16	0.175	Ω	
Gate Resistance	R_G	f = 1.0MHz open drain		12		Ω	
Dynamic Characteristics	•			•			
Input Capacitance	C _{iss}	\/ - 0\/		1676			
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$		59		pF	
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		2.5			
Total Gate Charge	Q_g			38.5			
Gate-Source Charge	Q_{gs}	$V_{DD} = 520V, I_{D} = 20A,$ $V_{GS} = 10V$		8		nC	
Gate-Drain Charge	Q_{gd}			15			
Turn-on Delay Time	t _{d(on)}			15			
Turn-on Rise Time	t _r	V _{DD} = 400V, I _D = 20A,		59			
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		121		ns	
Turn-off Fall Time	t _f			44			
Drain-Source Body Diode Character	istics						
Body Diode Forward Voltage	V _{SD}	$T_J = 25^{\circ}\text{C}, I_{SD} = 10\text{A}, V_{GS} = 0\text{V}$		0.9	1.2	V	
Reverse Recovery Time	t _{rr}			423		ns	
Reverse Recovery Charge	Q _{rr}	$V_R = 400V, I_F = I_S,$ $di_F/dt = 100A/\mu s$		5.3		μC	
Peak Reverse Recovery Current	I _{rrm}	.,		25		Α	

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 3.5A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. Identical low side and high side switch with identical $R_{\mbox{\scriptsize G}}$



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

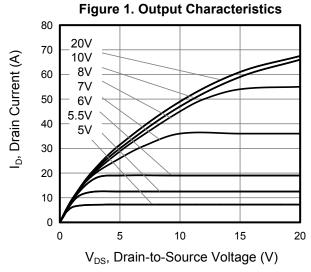
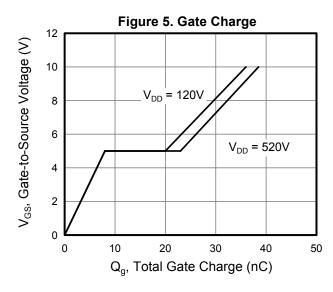
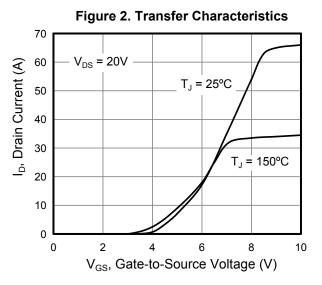
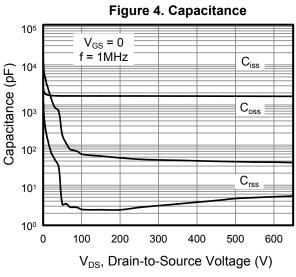
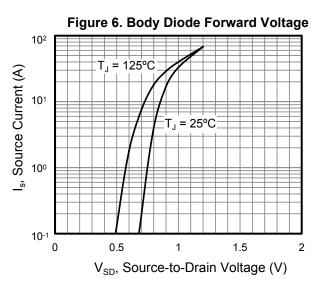


Figure 3. On-Resistance vs. Drain Current 0.19 $V_{GS} = 10V$ R_{DS(on)}, On-Resistance (Ω) 0.18 $T_J = 25^{\circ}C$ 0.17 0.16 0.15 0.14 0.13 0.12 0 10 20 I_D, Drain Current (A)











Typical Characteristics $T_J = 25$ °C, unless otherwise noted

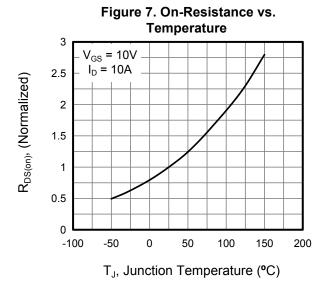


Figure 9. Transient Thermal Impedance For DFN 8*8

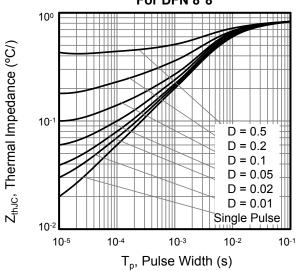


Figure 11. Typ. Coss Stored Energy

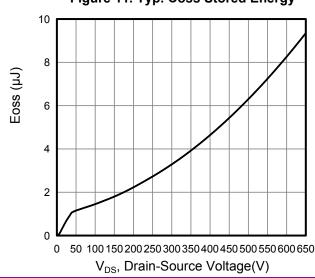


Figure 8. Breakdown voltage vs. Junction Temperature

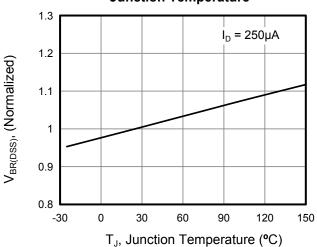


Figure 10. Safe Operation Area For DFN 8*8

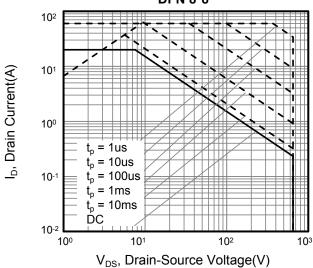




Figure A: Gate Charge Test Circuit and Waveform

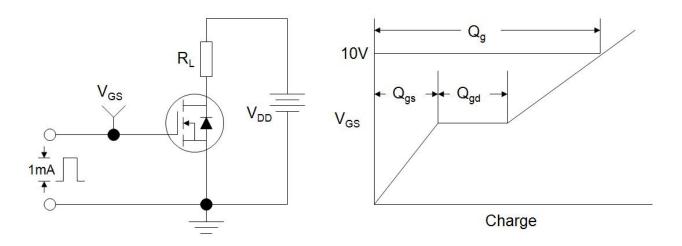


Figure B: Resistive Switching Test Circuit and Waveform

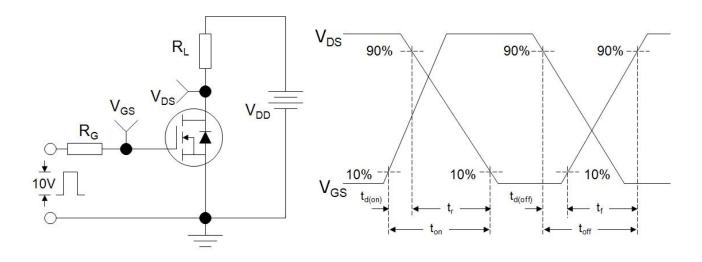
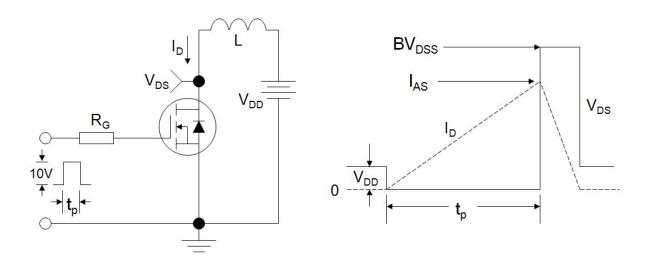
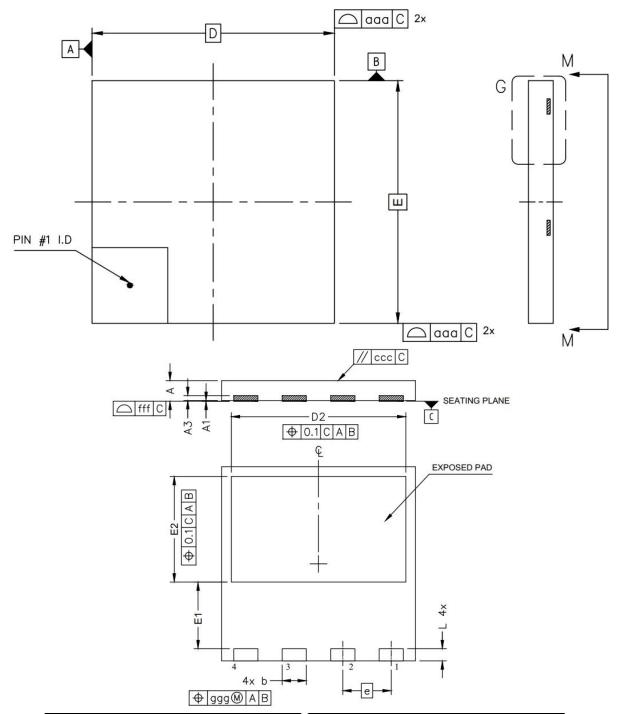


Figure C: Unclamped Inductive Switching Test Circuit and Waveform





DFN 8*8



Unit:mm						
Symbol	Min.	Nom	Max.			
Α	0.75	0.85	0.95			
A1	0.00	-	0.05			
A3	0.10	0.20	0.30			
b	0.90	1.00	1.10			
D	7.90	8.00	8.10			
Е	7.90	8.00	8.10			
D2	7.10	7.20	7.30			
E1	2.65	2.75	2.85			

Unit:mm					
Symbol	Min.	Nom	Max.		
E2	4.25	4.35	4.45		
е	2.00 BSC				
L	0.40	0.50	0.60		
aaa	0.10				
999	0.05				
ccc	0.05				
fff	0.05				



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